

HiPerFET™ Power MOSFET

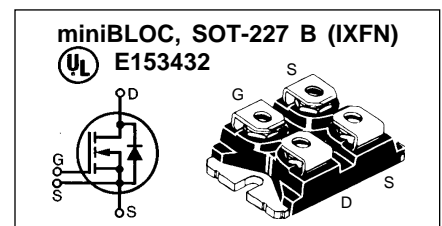
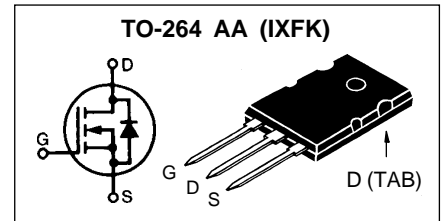
N-Channel Enhancement Mode

 Avalanche Rated, High dv/dt, Low t_{rr}

	V_{DSS}	I_{D25}	$R_{DS(on)}$	t_{rr}
IXFK 90N20	200V	90A	23mΩ	200ns
IXFN 106N20	200V	106A	20mΩ	200ns

Symbol	Test Conditions	Maximum Ratings			
		IXFK	IXFN		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	200	200	V	
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1\text{ M}\Omega$	200	200	V	
V_{GS}	Continuous	±20	±20	V	
V_{GSM}	Transient	±30	±30	V	
I_{D25}	$T_C = 25^\circ\text{C}$, Chip capability	90	106	A	
I_{D75}	$T_C = 75^\circ\text{C}$, limited by external leads	76	-	A	
I_{DM}	$T_C = 25^\circ\text{C}$, pulse width limited by T_{JM}	380	424	A	
I_{AR}	$T_C = 25^\circ\text{C}$	50	50	A	
E_{AR}	$T_C = 25^\circ\text{C}$	30	30	mJ	
dv/dt	$I_S \leq I_{DM}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2\ \Omega$	5	5	V/ns	
P_D	$T_C = 25^\circ\text{C}$	500	520	W	
T_J		-55 ... +150		$^\circ\text{C}$	
T_{JM}			150	$^\circ\text{C}$	
T_{stg}		-55 ... +150		$^\circ\text{C}$	
T_L	1.6 mm (0.063 in) from case for 10 s	300	-	$^\circ\text{C}$	
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1\text{ mA}$	t = 1 min t = 1 s	- -	2500 3000	V~ V~
M_d	Mounting torque Terminal connection torque	0.9/6 -	1.5/13 1.5/13	Nm/lb.in. Nm/lb.in.	
Weight		10	30	g	

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		Min.	Typ.	Max.
V_{DSS}	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	200		V
$V_{GH(th)}$	$V_{DS} = V_{GS}$, $I_D = 8\text{ mA}$	2		V
I_{GSS}	$V_{GS} = \pm 20\text{ V}_{DC}$, $V_{DS} = 0$			±200 nA
I_{DSS}	$V_{DS} = 0.8 V_{DSS}$, $T_J = 25^\circ\text{C}$ $V_{GS} = 0\text{ V}$, $T_J = 125^\circ\text{C}$			400 μA 2 mA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$, $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$	IXFK IXFN		0.023 Ω 0.020 Ω

 Chip capability $I_{D25} = 99\text{ A}$


G = Gate D = Drain
 S = Source TAB = Drain
 Either Source terminal at miniBLOC can be used as Main or Kelvin Source

Features

- Fast intrinsic rectifier
- Low package inductance
- Low $R_{DS(on)}$ HDMOS™ process
- International standard packages
- JEDEC TO-264 AA, epoxy meet UL 94 V-0, flammability classification
- miniBLOC, with Aluminium nitride isolation
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated

Applications

- DC choppers
- DC-DC converters
- Battery chargers
- Low voltage relays
- Synchronous rectification
- Temperature and lighting controls
- Switched-mode and resonant-mode power supplies

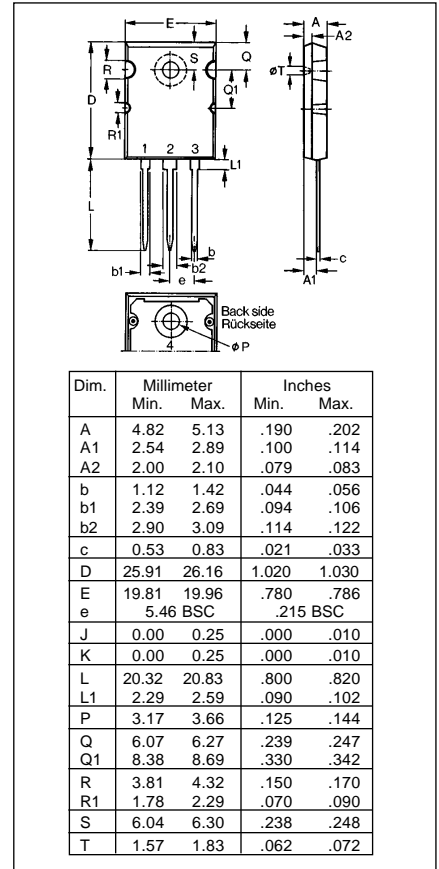
Advantages

- Easy to mount
- Space savings
- High power density

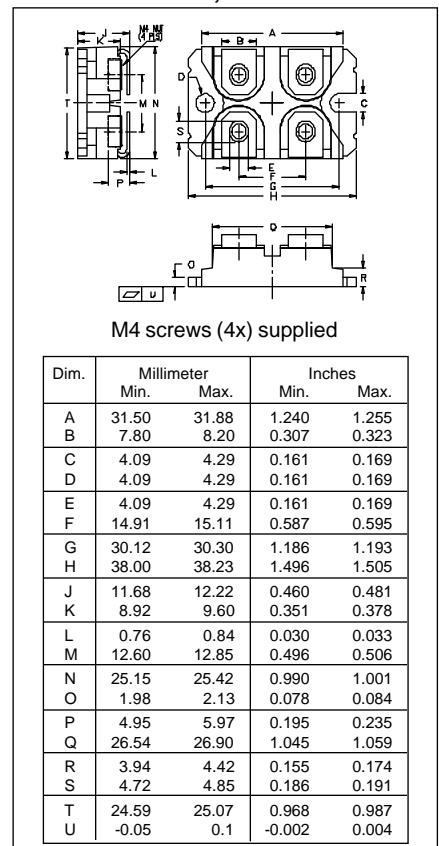
Symbol	Test Conditions	Characteristic Values		
		$(T_J = 25^\circ\text{C}, \text{ unless otherwise specified})$		
		Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10\text{ V}; I_D = 0.5 I_{D25}, \text{ pulse test}$		60	S
C_{iss}	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$		9000	pF
C_{oss}			1600	pF
C_{rss}			590	pF
$t_{d(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ $R_G = 1\ \Omega \text{ (External)}$		30	ns
t_r			80	ns
$t_{d(off)}$			75	ns
t_f			30	ns
$Q_{g(on)}$	$V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$		380	nC
Q_{gs}			70	nC
Q_{gd}			190	nC
R_{thJC}	TO-264 AA			0.25 K/W
R_{thCK}	TO-264 AA		0.15	K/W
R_{thJC}	miniBLOC, SOT-227 B			0.24 K/W
R_{thCK}	miniBLOC, SOT-227 B		0.05	K/W

Symbol	Test Conditions	Characteristic Values		
		$(T_J = 25^\circ\text{C}, \text{ unless otherwise specified})$		
		Min.	Typ.	Max.
I_S	$V_{GS} = 0$	IXFK		90 A
		IXFN		106 A
I_{SM}	Repetitive; pulse width limited by T_{JM}	IXFK		360 A
		IXFN		424 A
V_{SD}	$I_F = 100\text{ A}, V_{GS} = 0\text{ V}$ Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$			1.5 V
t_{TR}	$I_F = 50\text{ A}, -di/dt = 100\text{ A}/\mu\text{s}, V_R = 100\text{ V}$			200 ns
Q_{RM}			3	μC
I_{RM}			38	A

TO-264 AA Outline



miniBLOC, SOT-227 B



IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETS and IGBTs are covered by one or more of the following U.S. patents:

4,835,592	4,881,106	5,017,508	5,049,961	5,187,117	5,486,715
4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025

Fig.1. Output Characteristics

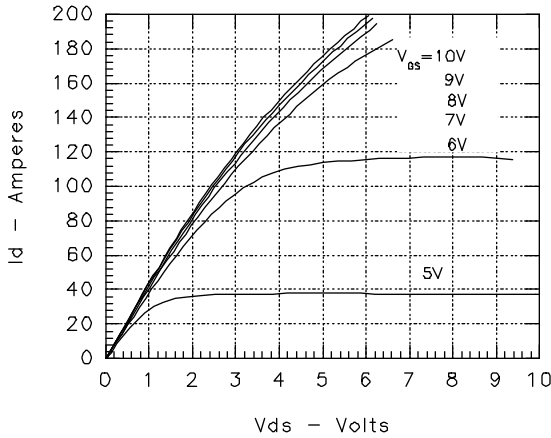


Fig. 2. Input Admittance

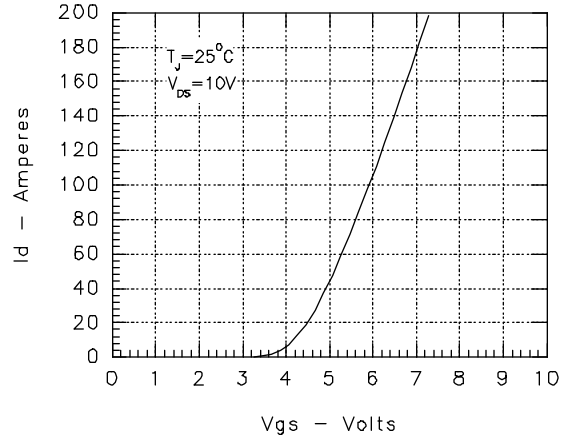


Fig. 3. Rds(on) vs. Drain Current

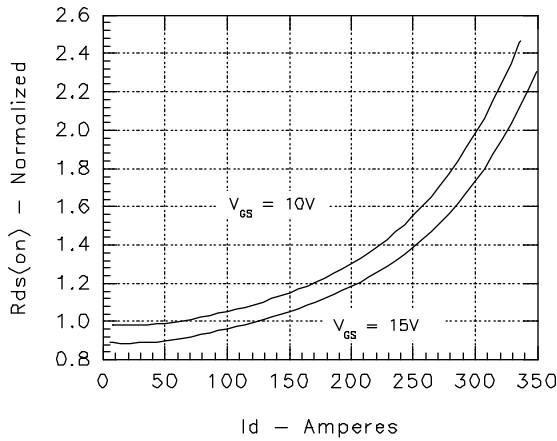


Fig. 4. Temperature Dependence of Drain to Source Resistance

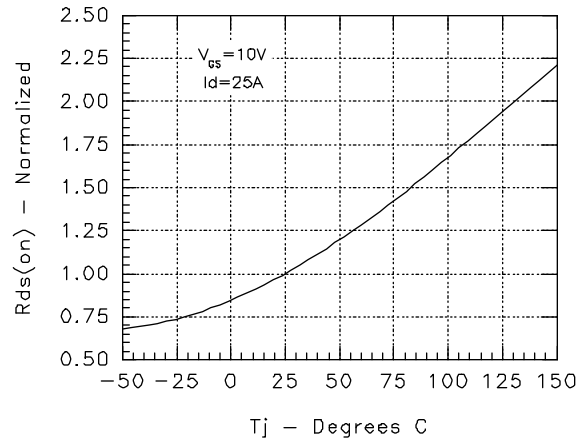


Fig. 5. Drain Current vs. Case Temperature

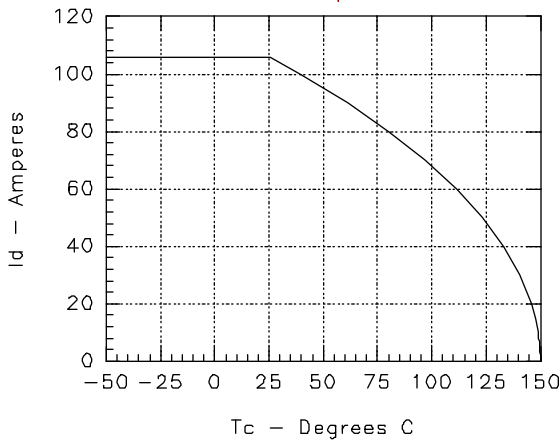


Fig. 6. Temperature Dependence of Breakdown Voltage and Threshold Voltage

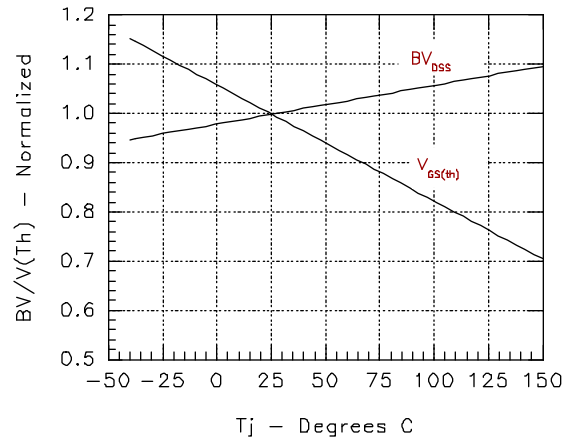


Fig. 7. Gate Charge

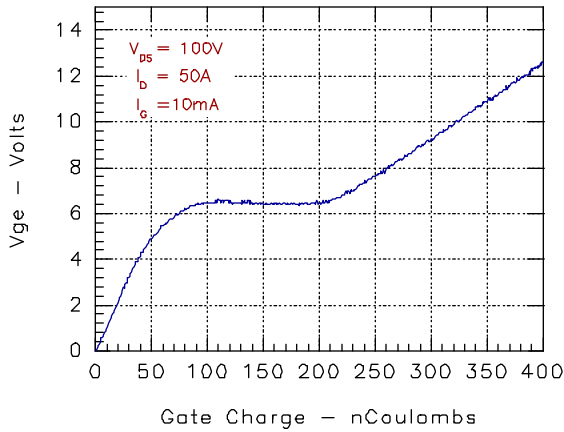


Fig. 8. Capacitance Curves

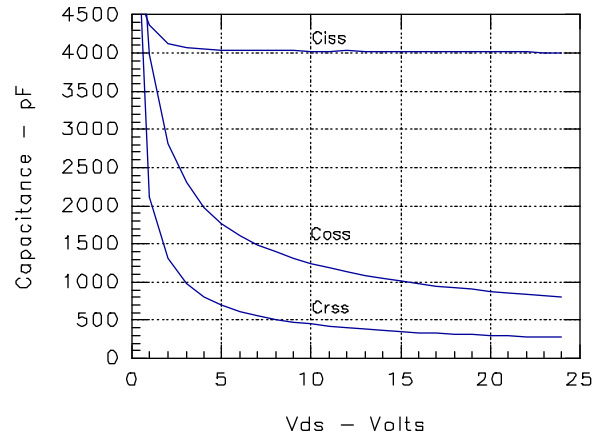


Fig. 9. Source Current vs. Source to Drain Voltage

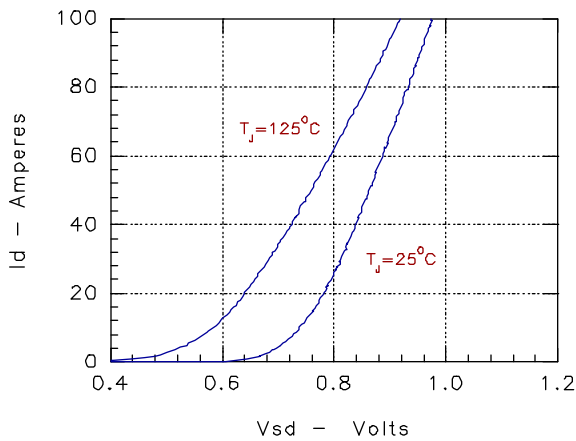
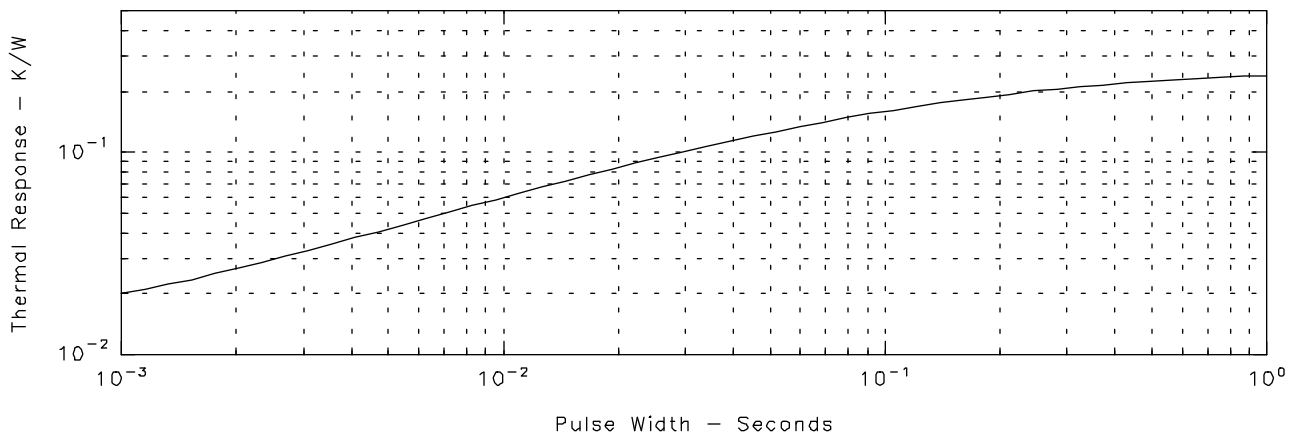


Fig. 10. Transient Thermal Impedance



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